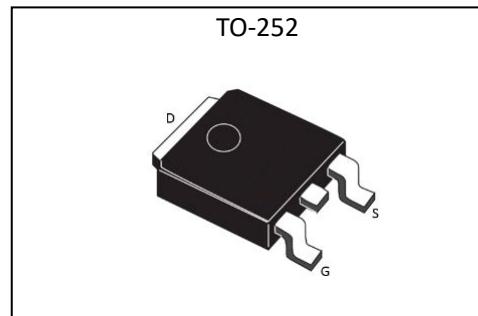


## Silicon N-Channel Power MOSFET

### General Description:

The HMR20N06L uses advanced trench technology and design to provide excellent  $R_{DS(ON)}$  with low gate charge. It can be used in a wide variety of applications. The package form is TO-252, which accords with the RoHS standard.

$V_{DSS}$	60	V
$I_D$	20	A
$P_D$	45	W
$R_{DS(ON).TYP.}$	27	$m\Omega$

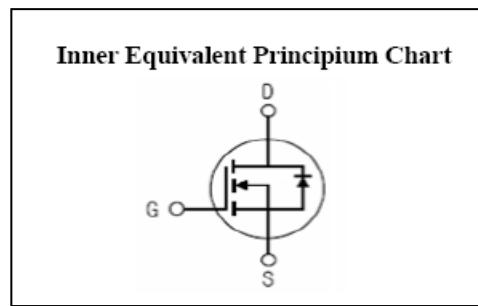


### Features:

- Fast Switching
- Low Gate Charge and  $R_{DS(ON)}$
- Low Reverse transfer capacitances
- 100% Single Pulse avalanche energy Test

### Applications:

- Power switching application
- Hard switched and high frequency circuits
- Uninterruptible power supply



### Absolute (T<sub>c</sub> = 25°C unless otherwise specified):

Symbol	Parameter	Rating	Units
$V_{DSS}$	Drain-to-Source Voltage	60	V
$I_D$	Continuous Drain Current	20	A
	Continuous Drain Current T <sub>c</sub> = 100 °C	14	A
$I_{DM}$	Pulsed Drain Current	60	A
$V_{GS}$	Gate-to-Source Voltage	$\pm 20$	V
$E_{AS}^{a2}$	Single Pulse Avalanche Energy	72	mJ
$E_{AR}^{a1}$	Avalanche Energy ,Repetitive	18	mJ
$I_{AR}^{a1}$	Avalanche Current	11	A
$dv/dt^{a3}$	Peak Diode Recovery dv/dt	5.0	V/ns
$P_D$	Power Dissipation	45	W
$T_J, T_{stg}$	Operating Junction and Storage Temperature Range	175, -55 to 175	°C
$T_L$	MaximumTemperature for Soldering	300	°C

**Electrical Characteristics (T<sub>c</sub> = 25°C unless otherwise specified):**

OFF Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
V <sub>DSS</sub>	Drain to Source Breakdown Voltage	V <sub>GS</sub> =0V, I <sub>D</sub> =250μA	60	--	--	V
ΔBV <sub>DSS</sub> /ΔT <sub>J</sub>	Bvdss Temperature Coefficient	I <sub>D</sub> =250μA, Reference 25°C	--	0.1	--	V/°C
I <sub>DSS</sub>	Drain to Source Leakage Current	V <sub>DS</sub> =60V, V <sub>GS</sub> =0V, T <sub>a</sub> =25°C	--	--	1	μA
		V <sub>DS</sub> =48V, V <sub>GS</sub> =0V, T <sub>a</sub> =125°C	--	--	250	
I <sub>GSS(F)</sub>	Gate to Source Forward Leakage	V <sub>GS</sub> = +20V	--	--	1	μA
I <sub>GSS(R)</sub>	Gate to Source Reverse Leakage	V <sub>GS</sub> = -20V	--	--	-1	μA

ON Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
R <sub>DS(ON)</sub>	Drain-to-Source On-Resistance	V <sub>GS</sub> =10V, I <sub>D</sub> =20A	--	27	35	mΩ
V <sub>GS(TH)</sub>	Gate Threshold Voltage	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250μA	1.0	1.7	2.5	V
Pulse width tp≤380μs, δ≤2%						

Dynamic Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
g <sub>fs</sub>	Forward Transconductance	V <sub>DS</sub> =5V, I <sub>D</sub> =5A	11	--	--	S
C <sub>iss</sub>	Input Capacitance	V <sub>GS</sub> =0V V <sub>DS</sub> =30V	--	500	--	pF
C <sub>oss</sub>	Output Capacitance	f=1.0MHz	--	60	--	
C <sub>rss</sub>	Reverse Transfer Capacitance		--	25	--	

Resistive Switching Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
t <sub>d(ON)</sub>	Turn-on Delay Time	I <sub>D</sub> =2A, V <sub>DD</sub> =30V	--	5	--	ns
t <sub>r</sub>	Rise Time		--	2.6	--	
t <sub>d(OFF)</sub>	Turn-Off Delay Time		--	2.3	--	
t <sub>f</sub>	Fall Time		--	5.5	--	
Q <sub>g</sub>	Total Gate Charge	I <sub>D</sub> =4.5A, V <sub>DD</sub> =30V, V <sub>GS</sub> =10V	--	47	--	nC
Q <sub>gs</sub>	Gate to Source Charge		--	6	--	
Q <sub>gd</sub>	Gate to Drain ( "Miller" )Charge		--	14	--	

**Source-Drain Diode Characteristics**

Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
$I_S$	Continuous Source Current (Body Diode)		--	--	20	A
$I_{SM}$	Maximum Pulsed Current (Body Diode)		--	--	60	A
$V_{SD}$	Diode Forward Voltage	$I_S=20A, V_{GS}=0V$	--	--	1.5	V
$t_{rr}$	Reverse Recovery Time	$I_S=10A, T_j = 25^\circ C$	--	35	--	ns
$Q_{rr}$	Reverse Recovery Charge	$dI_F/dt=100A/\mu s, V_{GS}=0V$	--	50	--	nC
Pulse width $t_p \leq 380\mu s, \delta \leq 2\%$						

Symbol	Parameter	Typ.	Units
$R_{\theta JA}$	Junction-to-Ambient	3.3	°C/W

<sup>a1</sup>: Repetitive rating; pulse width limited by maximum junction temperature

<sup>a2</sup>: EAS condition :  $T_j=25^\circ C, V_{DD}=30V, V_G=10V, L=0.5mH, R_g=25\Omega$

<sup>a3</sup>:  $I_{SD} = 10A, di/dt \leq 100A/\mu s, V_{DD} \leq BV_{DS}, \text{Start } T_j=25^\circ C$

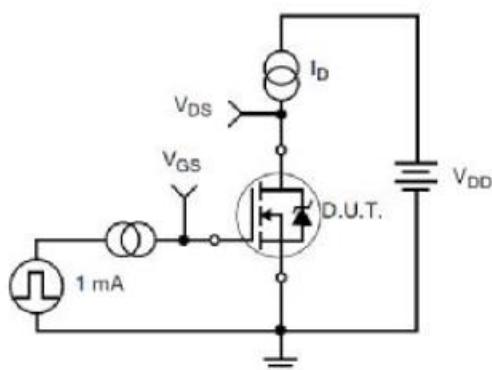
**Test Circuit and Waveform**


Figure 17. Gate Charge Test Circuit

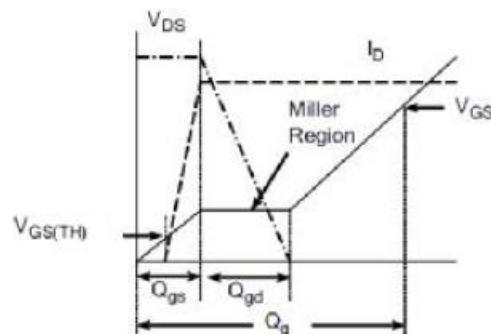


Figure 18. Gate Charge Waveform

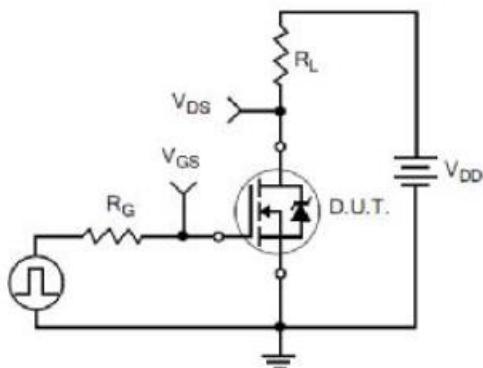


Figure 19. Resistive Switching Test Circuit

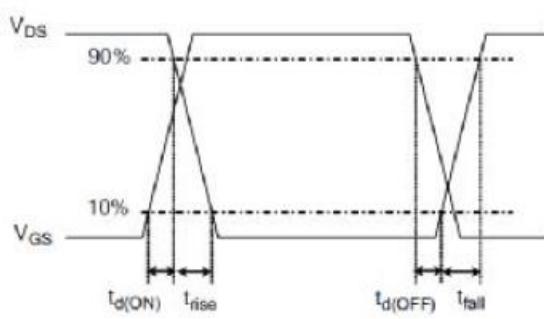
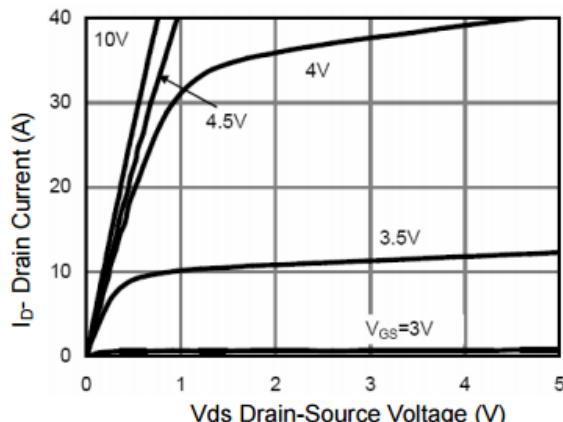
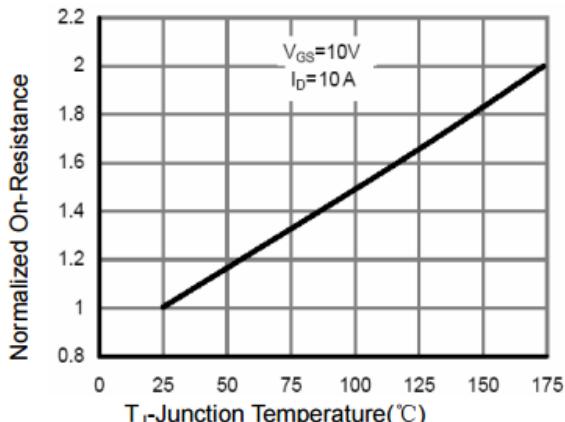
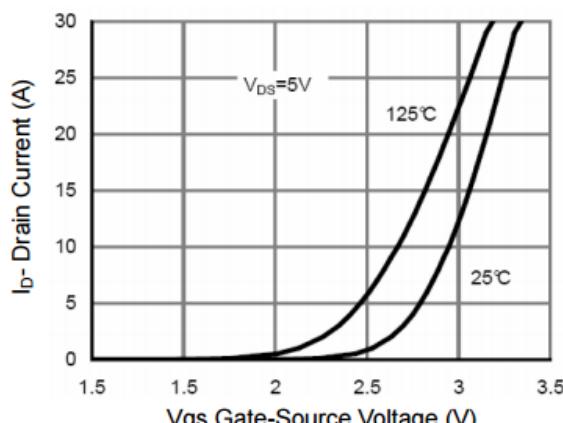
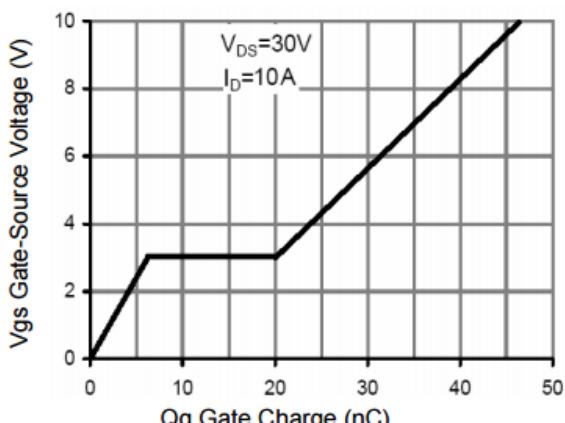
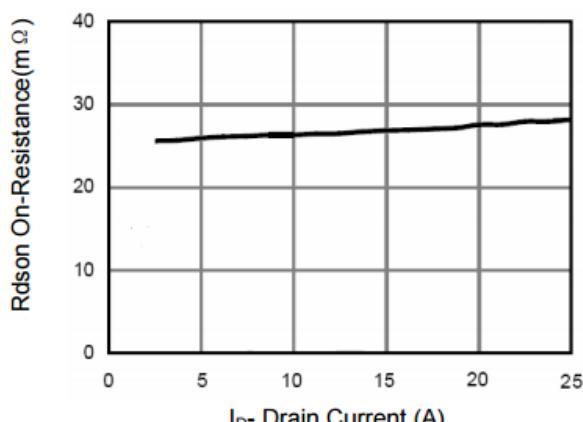
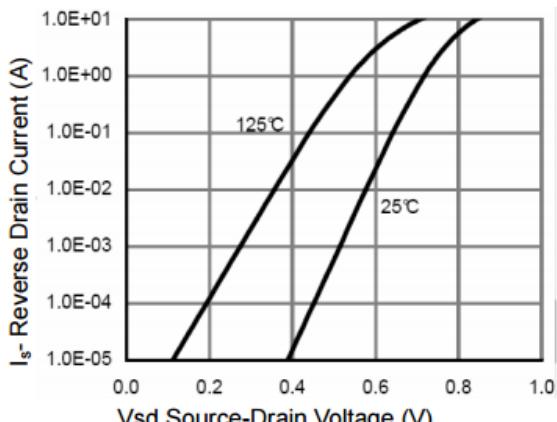
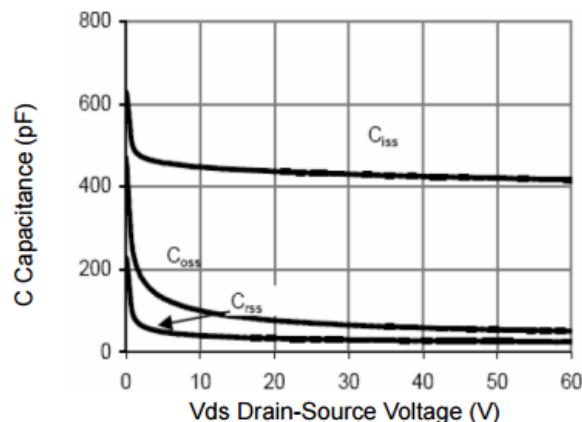
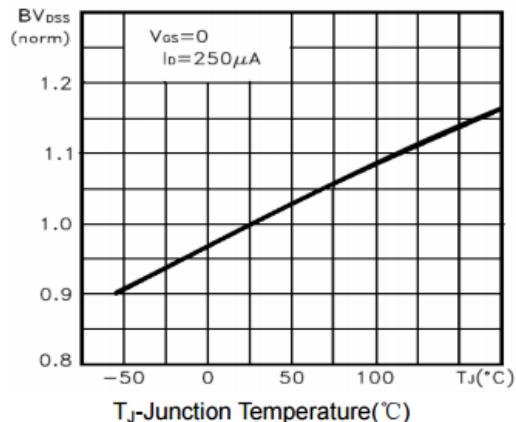
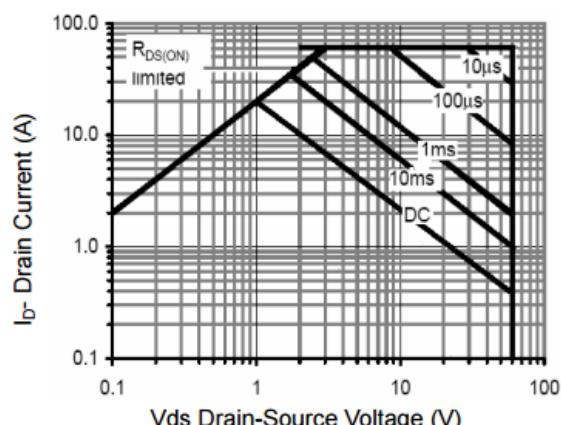
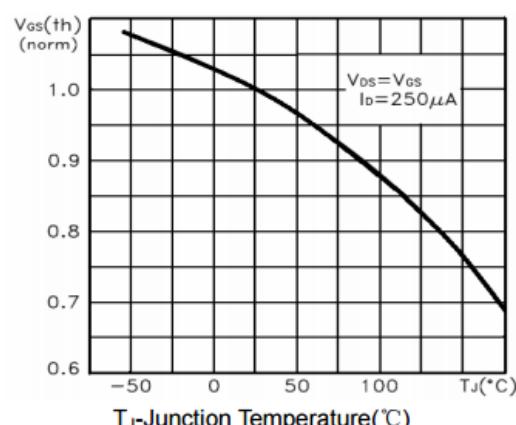


Figure 20. Resistive Switching Waveforms

**Characteristics Curve:**

**Figure 1 Output Characteristics**

**Figure 4 Rdson-Junction Temperature**

**Figure 2 Transfer Characteristics**

**Figure 5 Gate Charge**

**Figure 3 Rdson-Drain Current**

**Figure 6 Source-Drain Diode Forward**


**Figure 7 Capacitance vs Vds**

**Figure 9  $BV_{DSS}$  vs Junction Temperature**

**Figure 8 Safe Operation Area**

**Figure 10  $V_{GS(th)}$  vs Junction Temperature**
